




Search Notes 	Application/Control No. 10003720	Applicant(s)/Patent Under Reexamination DEW ET AL.
	Examiner Parry, Chris	Art Unit 2623

Notes	Date	Examiner
SEE ATTACHED SEARCH STRATEGY FROM EAST (USPAT; US-PGPUB; USOCR; EPO; JPO; ERWENT; IBM_TDB).	12/7/2005	CLP
CONSULTED EXAMINER SCOTT BELIVEAU ON AREAS OF SEARCH IN CLASS 725.	12/5/2005	CLP
SEE ATTACHED UPDATED SEARCH STRATEGY FROM EAST.	3/20/2006	CLP
725/63-72 - (TEXT SEARCH ONLY - SEE SEARCH HISTORY).	3/18/2006	CLP
CONSULTED CHRIS GRANT ON AREAS OF SEARCH IN CLASS 725.	3/17/2006	CLP
SEE ATTACHED UPDATED SEARCH STRATEGY FROM EAST.	5/23/2006	CLP
SEE ATTACHED UPDATED SEARCH STRATEGY FROM EAST.	7/14/2006	CLP
CONSULTED CHRIS GRANT ON AREAS OF SEARCH IN CLASS 725.	7/12/2006	CLP
CONSULTED PETER WILDER AND DOMINIC SALTARELLI (RE: CLAIM 1).	7/12/2006	CLP
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<i>Interference Searched</i> 	Application/Control No. 10003720	Applicant(s)/Patent Under Reexamination DEW ET AL.
	Examiner Parry, Chris	Art Unit 2623

Class	SubClass	Date	Examiner
TEXT SEARCH ONLY	PG-PUB Only	07/14/2006	CLP

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	<p>Examiner</p> <p>Parry, Chris</p>	<p>Art Unit</p> <p>2623</p>

Class	SubClass	Date	Examiner
725	37-39	12/2/2005	CLP
725	46	12/2/2005	CLP
725	85	12/2/2005	CLP
725	78	12/2/2005	CLP
725	13	12/2/2005	CLP
UPDATED	ABOVE	3/20/2006	CLP
725	9	3/20/2006	CLP
725	14	3/20/2006	CLP
UPDATED	ABOVE	5/23/2006	CLP
UPDATED	ABOVE	7/13/2006	CLP
725	50-53	7/13/2006	CLP
725	72	7/12/2006	CLP
725	68	7/12/2006	CLP
725	63	7/12/2006	CLP

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